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SHIGA7.051APC

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant : Takeshita et al.  
Appl. No. : U.S. National Phase of  
PCT/JP2004/017405  
Filed : Herewith  
For : POSITIVE RESIST  
COMPOSITION AND METHOD  
FOR FORMING RESIST  
PATTERN  
Examiner : Unassigned  
Group Art Unit : Unknown

**CERTIFICATE OF MAILING**

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

May 25, 2006

(Date)

Neil S. Bartfeld, Ph.D., Reg. No. 39,901

**PRELIMINARY AMENDMENT**

**Mail Stop PCT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Prior to examination of the above-referenced application, please enter the following amendments:

**Amendments to the Specification** begin on page 2 of this paper.

**Remarks** begin on page 3 of this paper.